| Special Test Request Form STR Numb   |   |  |  |
|--|---|--|--|
| Part 1 – Test Definition Section   |   |  |  |
| Test Title: Investigation of trigger requests during dead time with a single CAL Module  | Test Requestor: L.Wai   |  |  |
| <b>Test Purpose and Justification</b> :<br>Analysis of muon data from STR33 has revealed that the excess counts<br>of spurious trigger requests from CAL-LO and CAL-HI. These reques<br>Comparison with data from SVAC runs during 2, 4, and 6 towers indic<br>increasing with increasing numbers of towers. Why the rate (or likelih<br>depends on the number of towers being tested remains a mystery. | s in the GEM Discarded counter are the result<br>ats have a particular time signature.<br>cates that the rate of discarded events is<br>lood of occurrence) of these discarded events       |  |  |
| The working hypothesis from the CAL group is that these discarded ev<br>in the CAL-TEM system. This pickup is independent of the trigger so<br>some GCFEs are more susceptible to retriggering than others, so we sp<br>tracer of varying susceptibility. Thus it is important to investigate indi<br>available to the subsystems).  | vents are the result of pickup of readout noise<br>urce. Module-level testing has shown that<br>beculate that the discarded events are another<br>vidual Modules with a GASU (which was not |  |  |
| We propose to perform a test similar to STR33 on individual Towers in trigger source. We set CAL FLE and FHE thresholds to their flight va the CAL-LO and CAL-HI triggers.   | n the LAT, except also using a 1kHz external<br>lues (as in STR33) and systematically disable   |  |  |
| Test Description:  |   |  |  |
| 1. Use existing schema for bay 1 only (used for Trigger group treq scans).   |   |  |  |
| 2. LAT can have any rotational orientation for this test.  |   |  |  |
| 3. Setup the external trigger for 1kHz periodic from the pulse generator.  |   |  |  |
| 4. Collect 5 minutes each of End2End run config IDs B-24, B-25 (no cal lo), B-26 (no cal high)   |   |  |  |
| 5. Repeat for each other bay in the grid, using the corresponding single bay schema, with the following sequence: 5,12,13, 8, 9, 0, 4  |   |  |  |
| 5. If it appears we will run out of time due to schedule constraints, delete B-24 tests.   |   |  |  |
| '. If data volumes are a problem for any of the runs on bays 0 and/or 4, abort the remainder of the runs for that bay.   |   |  |  |
| GSE Configuration:   |   |  |  |
| EGSE: Current configuration used for 8 tower test under LATTE 4  |   |  |  |
| LAT Configuration:   |   |  |  |
| 8-towers.  |   |  |  |
| Expected Results/Acceptance Criteria:  |   |  |  |
| Offline results: Analysis of GEM discarded event distribution and tim STR33  | e structure using s/w tools developed for   |  |  |
| Acceptance criteria: Data taking completes.  |   |  |  |
| Expected Duration:   |   |  |  |
| Test duration: 6 hr including setup  |   |  |  |
|  |   |  |  |

Expected Analysis Duration:

1 day

# **Test Procedure**:

Based on STR33

# Test Script:

e2e runs B-24, B-25, B-26

# Part 2 – Impact Assessment Section

#### **Procedure development:**

Write down the steps in the work order; use existing procedures for tests.

## Script development and checkout:

None.

### Impact to schedule:

6-hrs for power-on, test, power-off of the LAT.

#### Risk Assessment:

No significant risk

#### **Required Resources**:

- 1-hr of Brian Grist to write the work order
- 6-hrs of test conductor/operator/QA for LAT test

### **Other Affected Parties:**

SVAC/IFCT - offline analysis of data for results and post-test report.

## **Part 3: Signature Approval:**

| <b>Required Authorizations</b> | Printed Name  | Signature           | Date         |
|--------------------------------|---|---------------------|--------------|
| Quality                        | Joe Cullinan  | (Signature on file) | Sept 19,2005 |
| I&T                            | Elliott Bloom   | (Signature on file) | Sept 17,2005 |
| Program Office                 | Lowell Klaisner or Dick Horn                              | (Signature on file) | Sept 19,2005 |
| Systems Engineering            | Pat Hascall   | (Signature on file) | Sept 19,2005 |
| Affected S/S managers          | N/A   |                     |              |
| Instrument Scientist           | Steve Ritz or Eduardo do Couto e<br>Silva/Anders Borgland | (Signature on file) | Sept 19,2005 |
| IFCT                           | Larry Wai   | (Signature on file) | Sept 19,2005 |
| Calorimeter                    | Eric Grove  | (Signature on file) | Sept 19,2005 |
| Other                          | N/A   |                     |              |
| Other                          | N/A   |                     |              |